

**Notice of References Cited**

Application/Control No.

10/028,744

Applicant(s)/Patent Under  
Reexamination  
TAKEDA ET AL.

Examiner

Michael O'Neill

Art Unit

3713

Page 1 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,281,833	08-1981	Sandler et al.	463/3
	B	US-4,314,236	02-1982	Mayer et al.	340/384.71
	C	US-5,026,051	06-1991	Lowe et al.	463/35
	D	US-5,052,685	10-1991	Lowe et al.	463/35
	E	US-5,095,798	03-1992	Okada et al.	463/35
	F	US-5,390,938	02-1995	Takeya, Noriyoshi	463/35
	G	US-5,556,107	09-1996	Carter, Andrew L.	463/35
	H	US-5,735,743	04-1998	Murata et al.	463/35
	I	US-5,768,393	06-1998	Mukojima et al.	381/17
	J	US-5,862,229 A	01-1999	Shimizu, Hideaki	381/17
	K	US-5,993,318 A	11-1999	Kousaki, Tatsuya	463/35
	L	US-6,146,276 A	11-2000	Okuniewicz, Douglas M.	463/35
	M	US-6,149,523 A	11-2000	Yamada et al.	463/31

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/028,744	Applicant(s)/Patent Under Reexamination TAKEDA ET AL.	
	Examiner Michael O'Neill	Art Unit 3713	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2001/0006909	07-2001	MIRASAKI et al.	463/35
	B	US-6,309,301 B1	10-2001	Sano, Nobuyoshi	463/35
	C	US-6,319,130 B1	11-2001	Ooseki et al.	463/43
	D	US-2001/0046895	11-2001	Kondo et al.	463/30
	E	US-6,347,998 B1	02-2002	Yoshitomi et al.	463/42
	F	US-6,361,439 B1	03-2002	Kawamoto, Yoshinori	463/35
	G	US-6,390,919 B1	05-2002	Kobayashi et al.	463/36
	H	US-2002/0094865 A1	07-2002	ARAKI et al.	463/35
	I	US-6,464,585 B1	10-2002	Miyamoto et al.	463/35
	J	US-6,425,827 B1	07-2002	Nimura, Shinobu	463/35
	K	US-6,527,639 B2	03-2003	Suzuki, Hideyuki	463/35
	L	US-6,544,122 B2	04-2003	Araki et al.	463/35
	M	US-6,572,475 B1	06-2003	Okabe et al.	463/30

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

**Notice of References Cited**

Application/Control No.

10/028,744

Applicant(s)/Patent Under  
Reexamination  
TAKEDA ET AL.

Examiner

Michael O'Neill

Art Unit

3713

Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,599,195 B1	07-2003	Araki et al.	463/43
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.